

FGH40N60SMDF 600V, 40A Field Stop IGBT

Features

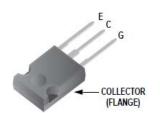
- Maximum Junction Temperature : T_J =175°C
- Positive Temperaure Co-efficient for easy parallel operating
- High current capability
- Low saturation voltage: $V_{CE(sat)} = 1.9V(Typ.) @ I_C = 40A$
- · High input impedance
- Fast switching
- Tighten Parameter Distribution
- RoHS compliant

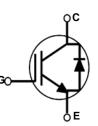
Applications

- Solar Inverter, UPS, SMPS, PFC
- Induction Heating

General Description

Using Novel Field Stop IGBT Technology, Fairchild's new series of Field Stop IGBTs offer the optimum performance for Solar Inverter, UPS, SMPS, IH and PFC applications where low conduction and switching losses are essential.





Absolute Maximum Ratings

Symbol	Description		Ratings	Units	
V _{CES}	Collector to Emitter Voltage		600	V	
V _{GES}	Gate to Emitter Voltage		± 20	V	
I _C	Collector Current	@ T _C = 25°C	80	A	
	Collector Current	@ T _C = 100 ^o C	40	A	
I _{CM (1)}	Pulsed Collector Current		120	A	
I _F	Diode Forward Current	@ T _C = 25°C	40	A	
	Diode Forward Current	@ T _C = 100 ^o C	20	A	
I _{FM (1)}	Pulsed Diode Maximum Forward Current		120	A	
P _D	Maximum Power Dissipation	@ T _C = 25°C	349	W	
. D	Maximum Power Dissipation	@ T _C = 100 ^o C	174	W	
TJ	Operating Junction Temperature		-55 to +175	°C	
T _{stg}	Storage Temperature Range		-55 to +175	°C	
Τ _L	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C	

Notes:

1: Repetitive rating: Pulse width limited by max. junction temperature

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Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance, Junction to Case	-	0.43	°C/W
$R_{\theta JC}$ (Diode)	Thermal Resistance, Junction to Case	-	1.45	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	-	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FGH40N60SMDF	FGH40N60SMDF	TO-247	-	-	30

Electrical Characteristics of the IGBT $T_{C} = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	teristics					
BV _{CES}	Collector to Emitter Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250 \mu A$	600	-	-	V
$\frac{\Delta BV_{CES}}{\Delta T_{J}}$	Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250\mu A$	-	0.6	-	V/ºC
I _{CES}	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$	-	-	250	μA
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$	-	-	±400	nA
On Charac	teristics					
V _{GE(th)}	G-E Threshold Voltage	I _C = 250μA, V _{CE} = V _{GE}	3.5	4.5	6.0	V
		$I_{\rm C} = 40$ A, $V_{\rm GE} = 15$ V	-	1.9	2.5	V
V _{CE(sat)}			-	2.1	-	V
Dynamic C	haracteristics					
Cies	Input Capacitance		-	1880	-	pF
C _{oes}	Output Capacitance	V _{CE} = 30V _, V _{GE} = 0V, f = 1MHz	-	180	-	pF
C _{res}	Reverse Transfer Capacitance		-	50	-	pF
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time		-	12	16	ns
t _r	Rise Time		-	20	28	ns
t _{d(off)}	Turn-Off Delay Time	V _{CC} = 400V, I _C = 40A,	-	92	120	ns
t _f	Fall Time	R _G = 6Ω, V _{GE} = 15V,	-	13	17	ns
Eon	Turn-On Switching Loss	Inductive Load, $T_C = 25^{\circ}C$	-	1.3	2.0	mJ
E _{off}	Turn-Off Switching Loss		-	0.26	0.34	mJ
E _{ts}	Total Switching Loss		-	1.56	2.34	mJ
t _{d(on)}	Turn-On Delay Time		-	15	-	ns
t _r	Rise Time	1	-	22	-	ns
t _{d(off)}	Turn-Off Delay Time	V _{CC} = 400V, I _C = 40A,	-	116	-	ns
t _f	Fall Time	$R_{G} = 6\Omega, V_{GE} = 15V,$	-	16	-	ns
Eon	Turn-On Switching Loss	Inductive Load, T _C = 175 ^o C	-	2.1	-	mJ
E _{off}	Turn-Off Switching Loss]	-	0.6	-	mJ
E _{ts}	Total Switching Loss	1	-	2.7	-	mJ

Electrical Characteristics of the IGBT (Continued)

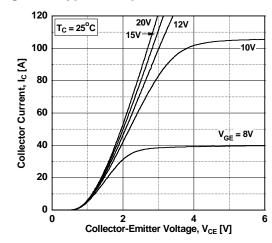
Symbol	Parameter	Test Conditions	Min.	Тур.	Max	Units
Qg	Total Gate Charge		-	119	180	nC
Q _{ge}	Gate to Emitter Charge	V _{CE} = 400V, I _C = 40A, V _{GE} = 15V	-	13	20	nC
Q _{gc}	Gate to Collector Charge	VGE - 10V	-	58	90	nC

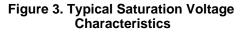
Electrical Characteristics of the Diode $T_{C} = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Тур.	Max	Units
V _{FM}	Diode Forward Voltage	I _F = 20A	$T_C = 25^{\circ}C$	-	1.3	1.7	V
VFM Diode i olward voltage	1F - 20A	T _C = 175°C	-	1.15	-		
E _{rec}	Reverse Recovery Energy		$T_{\rm C} = 175^{\rm o}{\rm C}$	-	138	-	uJ
t _{rr}	Diode Reverse Recovery Time	I _F =20A, dI _F /dt = 200A/μs	$T_{\rm C} = 25^{\rm o}{\rm C}$	-	70	100	ns
٩r		$F = 207$, $G = 2007/\mu^3$	T _C = 175 ^o C	-	210	-	
Q _{rr}	Diode Reverse Recovery Charge		$T_{\rm C} = 25^{\rm o}{\rm C}$	-	250	350	nC
α _{II}	Diodo Novoloo Novoloj enalgo		$T_{C} = 175^{\circ}C$	-	1875	-	

Typical Performance Characteristics

Figure 1. Typical Output Characteristics





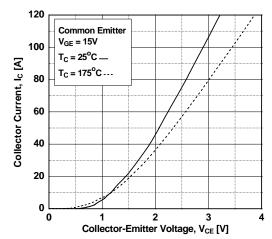


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

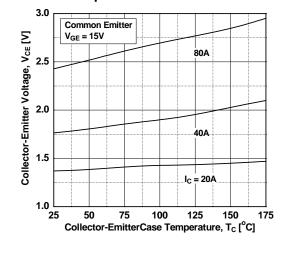


Figure 2. Typical Output Characteristics

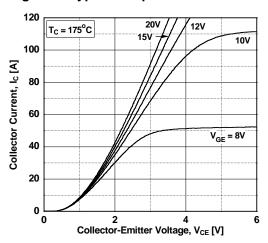


Figure 4. Transfer Characteristics

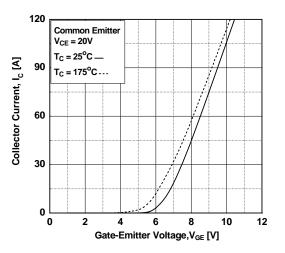
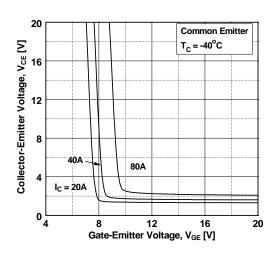
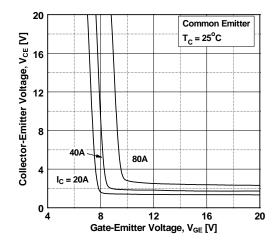


Figure 6. Saturation Voltage vs. V_{GE}



Typical Performance Characteristics

Figure 7. Saturation Voltage vs. V_{GE}





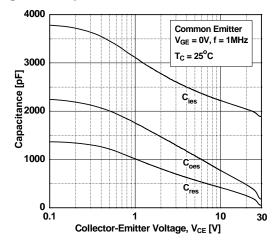


Figure 11. SOA Characteristics

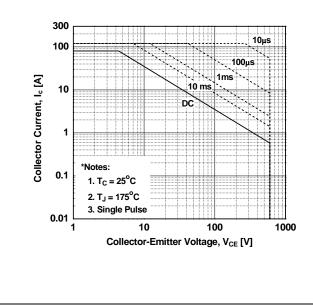


Figure 8. Saturation Voltage vs. V_{GE}

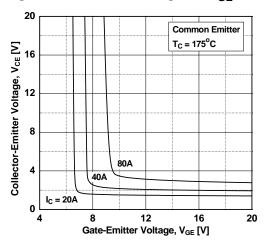


Figure 10. Gate charge Characteristics

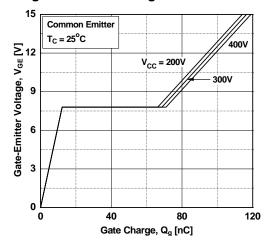
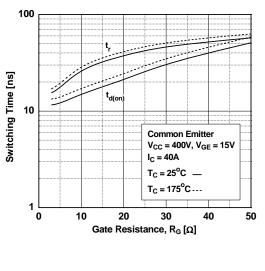
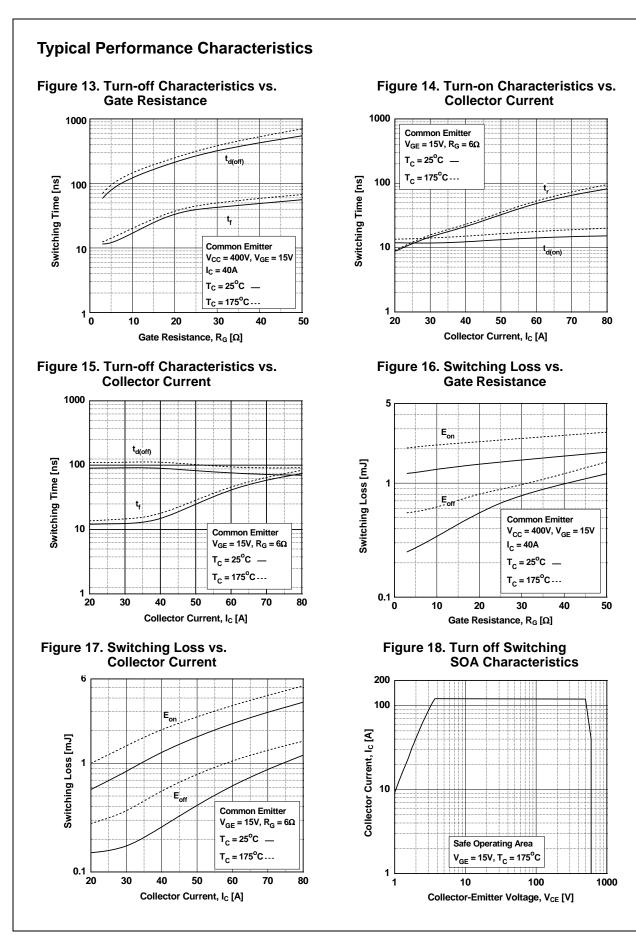


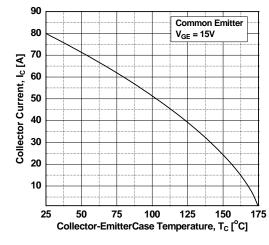
Figure 12. Turn-on Characteristics vs. Gate Resistance



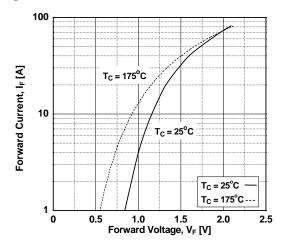


Typical Performance Characteristics

Figure 19. Current Derating









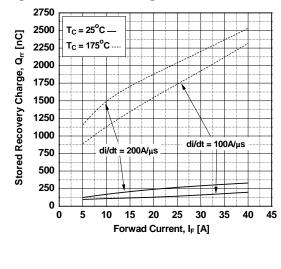
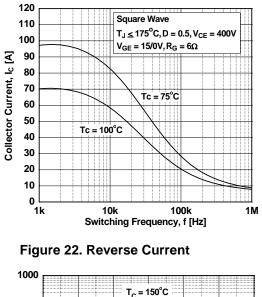


Figure 20. Load Current Vs. Frequency



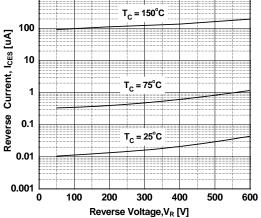
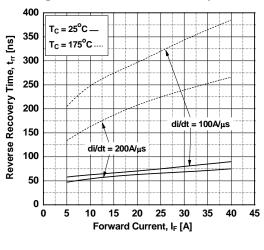
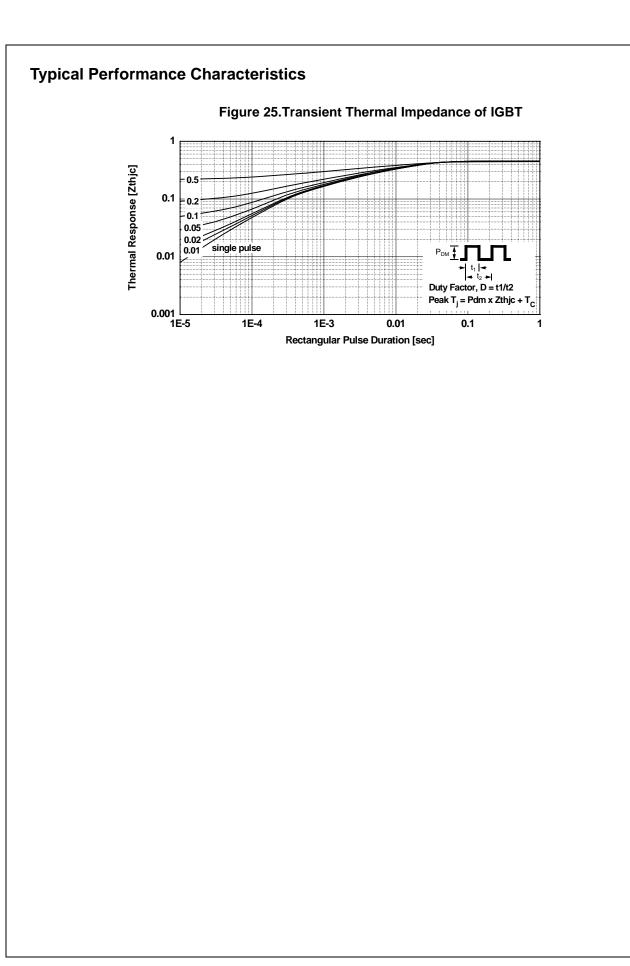
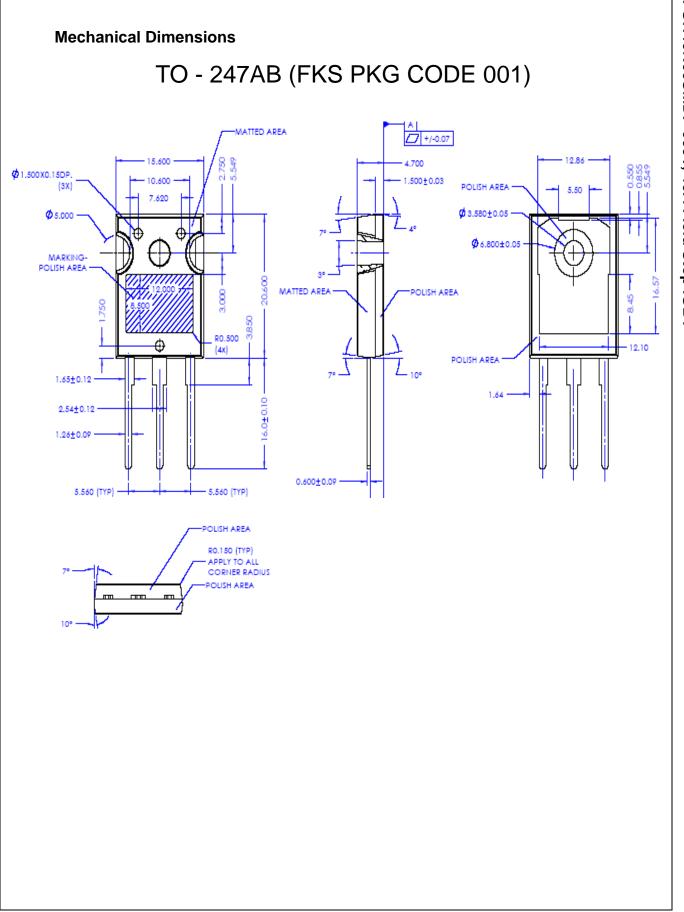
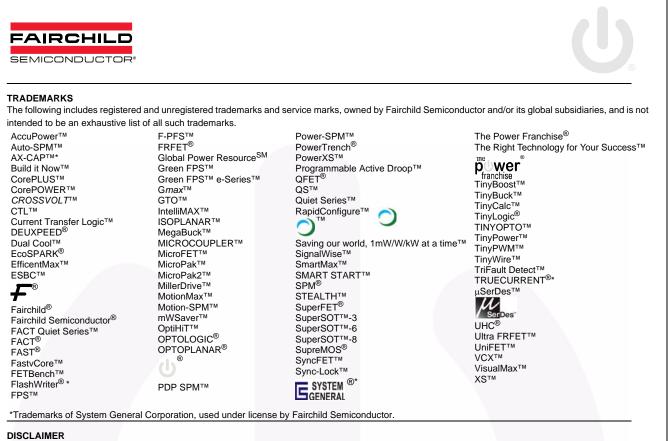


Figure 24. Reverse Recovery Time









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